

Notice of References Cited	Application/Control No. 10/694,465	Applicant(s)/Patent Under Reexamination GALLATIN ET AL.	
	Examiner Shambhavi Patel	Art Unit 2128	Page 1 of 1


U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,030,997	04-2006	Neureuther et al.	356/515
*	B	US-6,223,139	04-2001	Wong et al.	703/5
*	C	US-6,374,396	04-2002	Baggenstoss et al.	716/19
*	D	US-5,182,718	01-1993	Harafuji et al.	430/30
*	E	US-5,663,893	09-1997	Wampler et al.	716/19
*	F	US-5,723,233	03-1998	Garza et al.	430/5
*	G	US-6,078,738	06-2000	Garza et al.	716/21
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Fukuda et al. "Determination of High-Order Lens Aberration Using Phase/Amplitude Linear Algebra", 1999.
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.